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(54) Title: METHOD AND APPARATUS FOR AUTOMATICALLY GENERATING A PHASE LOCK LOOP (PLL)
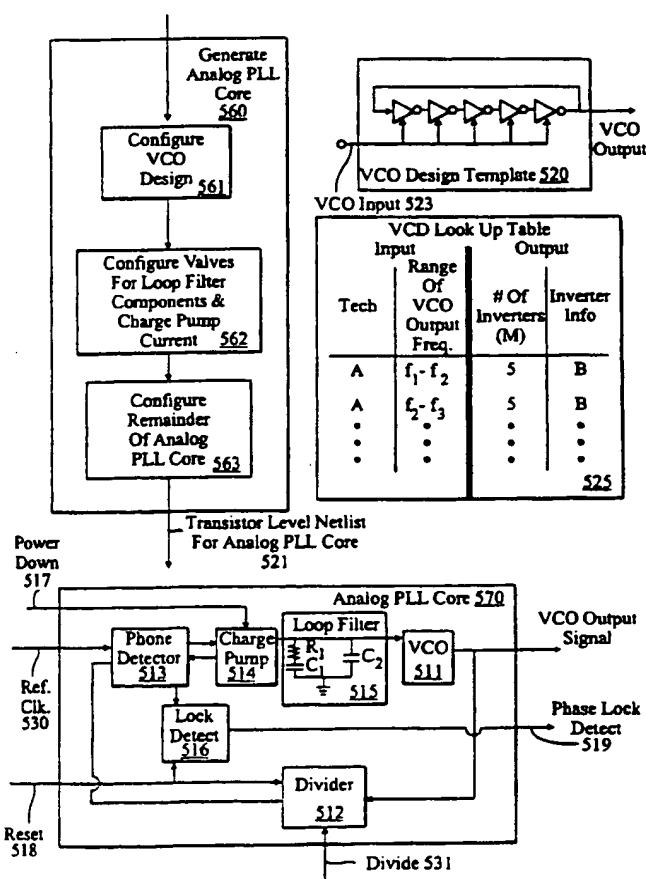
(57) Abstract: A method that automatically generates a design for an analog phase lock loop (PLL) core (560) in response to a desired clock frequency.

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Method And Apparatus For Automatically Generating A Phase Lock Loop (PLL)

This application hereby claims the benefit of a U.S provisional application filed on November 17, 1999 and given application number 60/166,096.

FIELD OF THE INVENTION

The field of invention relates generally to circuit design; and, more specifically, to the automatic generation of PLL related designs.

BACKGROUND

A Phase Lock Loop (PLL) is commonly used to generate one or more clock signals for a digital circuit. Figure 1 shows a typical PLL design. In Figure 1, the oscillator 101 is a voltage controlled oscillator (VCO) that produces an output signal having a frequency that is proportional to the voltage placed at its input 101a. The frequency of the oscillator 101 output signal is divided in the feedback loop by the divider 102. The divider 102 is typically a counter that triggers an edge at its output signal only after "N" edges are observed in the VCO 101 output signal. Thus, the divider 102 divides the frequency of the VCO 101 output signal by a factor of "N".

The PLL is used to effectively multiply the frequency of a reference clock by the factor of "N". That is, the PLL may be viewed as having an input that corresponds to a reference clock (Ref_Clock) and an output that corresponds to the VCO 101 output signal. The PLL settles to a stable operating point when the

frequency of the VCO 101 output signal is Nfo where fo is the frequency of the reference clock signal.

Phase comparator 103 produces an output based upon the phase difference between the divider 102 output signal and the reference clock signal. In the particular approach shown in Figure 1, a stream of pulses appear on the "upn" signal if the phase of the divider 102 output signal lags behind the reference clock. The width of the pulses within "upn" pulse stream are proportional to the amount of lag that exists. Similarly, a stream of pulses appear on the "down" signal if the phase of the divider 102 output signal is ahead of (i.e., "leads") the reference clock. The width of the pulses within the "down" pulse stream are proportional to the amount of lead that exists.

If a pulse stream appears on the "upn" signal, pulses of current are supplied by charge pump 104 to the loop filter 105. This raises the voltage at the VCO 101 input because loop filter 105 acts as an integrator. Raising the voltage at the VCO 101 input increases the frequency of the VCO 101 output signal. Similarly, if a pulse stream appears on the "down" signal, pulses of current are pulled by charge pump 104 from the loop filter 105 which lowers the voltage at the VCO 101 input. Lowering the voltage at the VCO 101 input decreases the frequency of the VCO 101 output signal. Note that loop 101,105 should also have adequate phase margin such that phase detector 103 does not confuse the proper output signaling (e.g., sending a "down" signal when the divider 102 output signal actually lags the reference clock).

During an initial synchronization time, the voltage at the VCO 101 input approaches its proper value (i.e., the voltage corresponding to a VCO output frequency of Nfo) as a result of the charge pump's activity. During this time, the charge pump usually supplies and/or pulls current to/from the loop filter 105 in accordance with the aforementioned pulse streams. Eventually, when the VCO 101 input voltage corresponds to a VCO output signal frequency of Nfo, the phase detector 103 does not recognize any error (because the divider output now has a frequency of fo) and the charge pump effectively stops pumping current to/from the charge pump 104. At this point, the PLL is stabilized and the voltage at the VCO 101 input remains substantially constant.

Since the dynamic activity of the charge pump 103 in relation to the design of the loop filter 105 determines the proper voltage at the VCO 101 input, the small signal transfer characteristics of the loop filter 105 are of noteworthy concern in PLL applications. Small signal loop filter 105 transfer characteristics as well as other PLL features (e.g., the design of the VCO 101, etc.) are commonly viewed as belonging to the "analog" domain of semiconductor chip circuit design. That is, a PLL emphasizes an analog as opposed to digital perspective.

Frequently, however, a semiconductor chip (as a whole) is designed substantially from the perspective of the "digital" domain and, as a result, it is common for semiconductor chip designers (i.e., individuals who design a semiconductor chip) to have skills that emphasize or are limited to the digital domain. As a result, semiconductor chip designers commonly experience

difficulty while attempting to design a suitable PLL for their semiconductor chip

because of a PLL's emphasis on the analog perspective.

SUMMARY OF INVENTION

A method that automatically generates a design for an analog phase lock

loop (PLL) core in response to a desired clock frequency.

BRIEF DESCRIPTION OF THE DRAWINGS

The present invention is illustrated by way of example, and not limitation,

in the Figures of the accompanying drawings in which:

Figure 1 shows a phase lock loop (PLL);

Figure 2 shows a semiconductor chip design flow that employs an automatically

generated PLL circuit;

Figure 3 shows a methodology for automatically generating a PLL circuit;

Figure 4 shows a graphical user interface (GUI) for entering desired clock output

signals;

Figure 5 shows a methodology for automatically generating an analog PLL core;

Figure 6 shows a methodology for automatically generating the values for the loop

filter components and the charge pump current of an analog PLL core;

Figure 7 shows a pair of open loop PLL transfer curves and a pair of PLL open

loop phase curves;

Figure 8 shows an embodiment of a simulator input GUI;

Figure 9 shows an embodiment of a simulator output;

Figure 10 shows an embodiment of an automatically generated PLL circuit;

Figure 11 shows an embodiment of an automatically generated clock shaping circuit associated with the PLL circuit of Figure 10;

Figure 12 shows examples of waveforms that may be produced with the clock shaping circuit of Figure 11;

Figure 13 shows a methodology that may be used to automatically generate the clock shaping circuit of Figure 11;

Figure 14 shows an embodiment of a programmable divider;

Figure 15 shows an embodiment of a methodology that may be used to automatically generate a layout for a PLL;

Figure 16A shows an embodiment of a configurable portion of a charge pump block; and

Figure 16B shows an embodiment of a configurable loop filter resistor.

DETAILED DESCRIPTION

Design Flow Overview

A solution to the problem described in the background is a software program that "automatically" designs a phase lock loop (PLL) for a semiconductor chip designer. As a result, the designer is shielded from comprehending analog concepts associated with PLL design and is allowed to focus his/her efforts on the digital aspects of a chip's design. Semiconductor chips (which are also referred to as integrated circuits (ICs)) are therefore efficiently developed because the time needed by a designer to develop his/her analog design skills (in order to design a PLL) is not expended.

An exemplary design methodology 200 that employs the use of automatic PLL generation software is shown in Figure 2. As seen in the example of Figure 2, the designer presents a desired input frequency 201, a description of the desired output clocks 202 and a desired technology 203 to a PLL generation software program 204. A desired technology 203 (also referred to as a "target" technology) identifies the particular semiconductor manufacturing process that the semiconductor chip will be manufactured with.

The PLL generation software program 204 then generates 214 a PLL related design (e.g., a model, netlist, circuit diagram, etc.) for use by the designer during the development of his/her semiconductor chip. The PLL related design presented by the program 204 may include or exclude various PLL details depending on when it is introduced to the designer during the semiconductor design process. Furthermore, more than one type of PLL representation may be

provided by the software program 214 to support the designer at various stages of the design process.

An analog PLL core (which may also be referred to as a "PLL core", an "analog core" and the like) may be generally described as a circuit having a VCO, loop filter and a phase detector, where the VCO and phase detector are communicatively coupled via a feedback arrangement (e.g., via a feedback divider). A PLL circuit may be generally described as a circuit that not only includes at least a representation or model of an analog PLL core but also includes circuitry that provides an input to the analog core (such as a circuit that feeds an input signal to the phase detector) and/or uses an output from the analog core (such as or a circuit that accepts the VCO output signal).

It is important to point out that the automatic PLL generation software may automatically generate an analog PLL core or may automatically generate a PLL circuit or both. Thus, although the following discussion concerns an embodiment where both an analog core and a PLL circuit are automatically generated, it should be understood that aspects of the present discussion apply to PLL generation software that automatically generates only an analog PLL core or only a PLL circuit.

Figure 2 shows an exemplary semiconductor chip design methodology 200 having automatic PLL circuit generation 214 . A standard design flow (i.e., a design flow without the support of an automatically generated PLL) exists within region 280 of Figure 2 (ignoring inputs to the process 280 as provided by the automatic PLL generation software 204). The automatically generated PLL circuit

is integrated into the design of a semiconductor chip at various stages of the

semiconductor chip's design process. Note that in the particular example of Figure

2, the PLL generation software 204 produces four file types for the designer: 1) a

behavioral level model 220; 2) a synthesis script 223; 3) a transistor level netlist 221;

and 4) a physical layout tile 222. Each of these is discussed in more detail below.

However, before continuing, it should be understood that alternative

mechanisms for integrating an automatically generated PLL into a semiconductor

chip design process may exist. As such, automatic PLL generation should not be

construed as limited to the particular design process flow shown in Figure 2 or as

discussed elsewhere in this description.

To promote efficient semiconductor chip design, a semiconductor chip may

be designed 230 at a high level of abstraction (which is commonly referred to as the

"behavioral level" or the Hardware Description Language (HDL) level). The

behavioral level describes functional building blocks of a semiconductor chip at a

high level. As such, a designer can efficiently design 230 a chip by interconnecting

various building blocks together.

The operation of the semiconductor chip as a cooperative whole (or one or

more portions thereof) may be efficiently observed via simulation. As part of the

behavioral level design 230 process, the designer may modify the design (or

perhaps the building blocks themselves) in light of these simulations. As seen in

the exemplary design flow embodiment 200 of Figure 2, a behavioral level model

220 is provided to the designer by the PLL generation program 204.

The behavioral level model 220 (which typically takes the form of a Verilog or VHDL compatible model) allows the designer to simulate, at a high level, the operation of his/her chip as it inter-works with (or otherwise depends upon) the operation of the PLL. In an embodiment, which is described in more detail further below, the behavioral level model 220 has an input clock and one or more output clocks having temporal characteristics (e.g., frequency, duty cycle and phase) specified by the designer (e.g., via entry of input parameters 201, 202 to the PLL generation software 204).

The PLL circuit design provided by the PLL generation software 204 may have both analog and digital components. For example, in various embodiments, the PLL circuit design is viewed as having an analog "core" (which corresponds to a basic PLL such as the PLL design shown in Figure 1) surrounded and/or supported by various digital functional units that add additional features to the functionality provided by the analog PLL core.

For example, digital clock shaping circuitry may be configured to follow the VCO (i.e., accept the VCO 101 output signal as an input) to craft the one or more output clocks 202 specified by the designer. The digital clock shaping circuitry is aptly described in the behavioral model 220 provided by the PLL generation software 204 (e.g., in an RTL HDL format) so that it may be easily formatted into an RTL netlist 233 by standard design flow procedures.

The analog PLL core, however, may be treated as a "black box" at the behavioral level. That is, in the same embodiment referred to above, the analog constituents of the analog core (e.g., the loop filter, VCO, charge pump, phase

detector, etc.) are not specifically described at the behavioral level. Rather, the

"black box" simply describes the designed for VCO output signal (e.g., by its

frequency) and may also describe temporal aspects of the analog core (such as the

time consumed to lock onto its input reference clock). More details are provided

toward the end of this description of an embodiment of a behavioral level model

220 that corresponds to the approach just described.

Once the designer is satisfied with the behavioral level design, an RTL

netlist 233 is created 230 that describes the digital portions of the designer's IC.

Note that the behavioral level model 220 provided by the automatic PLL circuit

generation software 204 may describe the digital portions of the PLL circuit at the

RTL level (e.g., with an RTL netlist). Thus, creating an RTL level netlist that

describes the digital portions of the PLL circuit involves simply removing the

"black box" that describes the analog PLL core at the behavioral level. A synthesis

script 233 may also be provided that allows the digital portions of the PLL circuit

to be mapped into layout information (e.g., in GDSII format) and a corresponding

transistor level netlist.

After an RTL netlist 233 describing the digital portions of a designer's IC has

been created, the RTL level netlist 233 is synthesized into a gate level netlist 238.

The gate level netlist 238 is then used to place, route and perform timing analysis

232 of the designer's IC. After the timing has been verified, a transistor netlist 237

is created and the layout 234 of the IC's design may commence.

Layout 234 is a process that defines the position and dimensions of the

transistors in an IC (and any interconnections between them). Layout information

may be stored in a GDS-II file or other type of file that stores physical layout

aspects of semiconductor chip.

As seen in the embodiment 200 of Figure 2, the automatic PLL generation

software 204 further provides the designer with: 1); a layout tile 222 (e.g., a GDS-II

file) that describes the layout of an analog PLL core; and 2) a transistor level netlist

221 of the analog PLL core. As such, enough information exists to completely

layout 234 the IC.

That is, the transistor level netlist 237 and GDS II information 239 provided

by the place, route and timing analysis 232 provides a full description of the digital

portions of the IC while the layout tile 222 and transistor level netlist 221 provided

by the automatic PLL circuit generation software 204 provides a full description of

the analog portions of the IC.

The layout is then verified 235 by comparing (also referred to as "back

annotating") the connections of a transistor netlist (that completely describes the

analog and digital portions of the IC) with the connections implemented in the

layout. When the layout is verified it is then checked against the semiconductor

design rules particular to the manufacturing process the chip is to be manufactured

with. Masks are then generated 236 and the chip is ready for manufacturing.

Alternate design flow embodiments exist. For example, in another

embodiment the designer is provided with a layout tile 222 and transistor level

netlist 221 having both digital and analog portions of a PLL circuit described by the

behavioral model 220. As such, an RTL netlist and synthesis script 223 need not be

provided by the automatic PLL generation software 204.

Automatic PLL Circuit Generation

Figure 3 shows an exemplary embodiment 314 of a methodology that may

be used to automatically generate a PLL circuit 214 as seen in the design flow 200

of Figure 2. The methodology 314 of Figure 3: 1) defines 350 the inputs and the

outputs of the circuitry to be automatically generated; 2) generates 360 a design for

an analog PLL core (the analog core may also be simulated and the results of the

simulation presented to the designer); 3) generates 370 a behavioral level model

that is used by the designer at the behavioral design level; and 4) generates 380 a

physical layout tile of the automatically generated circuit for use by the designer

during the layout of the semiconductor chip.

Thus as an example, referring to Figures 2 and 3: 1) the behavioral level

model 320 of Figure 3 corresponds to the behavioral model 220 of Figure 2; 2) the

transistor level netlist 321 of Figure 3 corresponds to the transistor level netlist 221

of Figure 2 (where the transistor level netlist 221 of Figure 2 corresponds to the

PLL's analog core as described above); and 3) the physical layout tile 322 of Figure

3 corresponds to the physical layout tile 222 of Figure 2.

Note that the inputs and outputs of the circuit to be automatically generated

may be defined 350 by: 1) presenting 330 a "clock display" graphical user interface

to the designer so that a description 302 of the output clocks to be derived from the

VCO output signal may be easily defined (as well as other information such as the

input clock frequency 301); and 2) computing 340 the VCO output signal frequency

and the division performed by the divider located in the feedback path of the PLL

(e.g., divider 102 of Figure 1).

Figure 4 shows an exemplary graphical user interface 400 that may be

presented to the designer. Through the graphical user interface 400, the designer

can effectively specify a description of the various output clocks to be produced by

the PLL circuit. A clock may be defined by its frequency, duty cycle and phase. In

the example shown in Figure 4, the designer has specified four output clocks, the

waveforms of which are shown respectively as waveforms 401 through 405.

In the graphical user interface embodiment of Figure 4, the designer triggers

the addition of a new output clock by a control key, or mouse button click or other

affirmative action. The designer then enters the frequency of the output clock into

a window. A waveform is next displayed having the frequency specified by the

designer. Figure 4 shows an example of the windows 406 through 410 through

which the frequency is specified for each of the four corresponding output clock

waveforms 401 through 405. In an alternate embodiment, the user specifies the

output clock frequencies before the graphical user interface is presented such that

the graphical user interface is limited to defining the duty cycle and phase of an

output clock.

After the designer has specified the frequency of an output clock, a duty

cycle may be specified for the output clock via the duty cycle button 411. For

example, by pointing and clicking on a particular waveform, the corresponding

output clock is "highlighted". Thus, when the designer subsequently points and

clicks upon the duty cycle button 411, the duty cycle of the highlighted output

clock can be adjusted. In an embodiment, another window appears that allows the

designer to further specify the highlighted clock's duty cycle. The waveform of the highlighted clock is then altered to reflect the designer's desired duty cycle.

The phase position of a highlighted clock (i.e., the position of the waveform along the time (horizontal) axis) may be adjusted via the delay and advance buttons 412, 413 respectively. By selecting the delay button 412, the waveform is moved backward to provide a relative phase lag. By selecting the advance button 413, the clock waveform is advanced forward to provide a relative phase lead.

Referring briefly back to Figure 3, note that a description 302 of the output clocks has been provided once: 1) the number of output clocks and the frequency of each has been specified 304; and 2) the phase and duty cycle of each output clock has been specified 305. The input clock frequency 301 for the circuit to be automatically generated may also be entered through the graphical user interface 400.

The graphical user interface 400 embodiment of Figure 4 also allows the waveforms to be viewed from a number of different visual perspectives via the zoom out button 414 (which increases the temporal (i.e., horizontal) scaling of the waveform images), the zoom in button 415 (which decreases the temporal scaling of the waveform images), the pan left button 416 (which moves the view of the displayed waveforms to the left), and the pan right button 417 (which moves the view of the displayed waveforms to the right). The displayed waveforms 401 though 405 can also be automatically brought back to a default temporal scaling via the zoom reset button 418.

Note that the VCO output signal waveform (referred to in Figure 4 as the
Vco Clk 419) may also be displayed. The output clocks are derived from the VCO
output signal. That is, the frequency of the output clocks are achieved by
"dividing down" from the frequency of the VCO output signal. For example,
referring to Figure 4, waveform 401 corresponds to dividing down the VCO output
signal frequency by a factor of 2.0 (i.e., 200MHz/2 = 100MHz), waveform 402
corresponds to dividing down the VCO output signal by a factor of 4.0 (i.e.,
200MHz/4 = 50MHz), etc.

The designer may calculate the proper VCO output signal frequency for his
or her application and enter it into the automatic circuit generation software.
Alternatively, an algorithm may be executed by the software that determines the
proper VCO output signal frequency as a function of the output clock waveforms
401 through 405 that are crafted by the designer.

For example in an algorithm embodiment supported by the waveform
display of Figure 4, the VCO output signal frequency is configured to be twice that
of the maximum output clock signal frequency. That is, a VCO output signal
frequency "divide down" of 2.0 is always implemented to establish the frequency
of the fastest output clock. As such, note that the fastest waveform 401 of Figure 4
has a frequency of 100MHz while the VCO output signal has a frequency of
200MHz.

Depending on the circuitry that crafts the output clock waveforms, the
minimum allowable pulse width and the temporal increment for all phase
adjustments may be limited to integer multiples of the VCO output clock signal

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period. For example, for a 200MHz VCO output clock waveform, pulse widths

and/or phase adjustments are limited to increments of 5ns (i.e., because

1/200MHz = 5ns). Thus, available pulse widths and/or phase adjustments are

limited to 5ns, 10ns, 15ns, 20ns, etc.

More sophisticated algorithm schemes (as compared to the embodiment

described just above) may be employed to automatically determine the VCO

output signal frequency. For example, in an alternative embodiment, the VCO

output signal frequency is determined by referring to the minimum pulse width,

the minimum phase position (i.e., the narrowest time between edges of separate

output clocks) and the maximum output clock frequency across all the output

clocks specified by the designer.

In this alternative embodiment, the proper VCO output signal frequency

corresponds to whichever of these parameters corresponds to the highest

frequency. For example, if a designer configures a selection of output clocks that

demonstrate (across all of the output clocks) a minimum pulse width of 5ns, a

minimum phase position of 10ns, and a maximum frequency of 50Mhz, the

minimum pulse width of 5ns corresponds to the highest frequency (i.e., 1/5ns =

200MHz; 1/10ns = 100MHz; and 50MHz x2 = 100MHz). Thus, a VCO output

signal frequency of 200MHz is configured for the PLL.

Again, depending on the circuitry that crafts the output clock waveforms,

the minimum allowable pulse width and the temporal increment for all phase

adjustments may be limited to integer multiples of the VCO output clock signal

period. The automatic circuit generation software may be configured to

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implement sufficiently sophisticated output clock waveform shaping logic that does not limit the duty cycle and phase position choices, as described above, once the VCO output clock signal has been determined. Thus, the automatic generation software described herein should not be construed as being so limited.

Once the VCO output signal frequency has been determined, the divider ratio of the feedback divider (i.e., divider 102 of Figure 1) may be calculated. Equation 1 below provides a standard equation for determining the dividing down ratio "N" performed by the feedback divider:

N = VCO output signal frequency / reference clock frequency

Eqn. 1

where reference clock frequency corresponds to the frequency of the Ref_Clock signal shown in Figure 1.

In an embodiment, N is an integer. Thus, the designer understands that the automatically generated PLL circuit is to be limited to a VCO output signal frequency and reference clock frequency combination having an integer ratio relationship with respect to one another.

In a more sophisticated embodiment, fractional N synthesis is employed to modulate the feedback divider such that it divides down the VCO output signal frequency by a non integer. As such, the designer is not limited to a VCO output signal frequency and reference clock frequency combination having an integer ratio relationship with respect to one another.

In a fractional N synthesis approach, the circuitry configured by the automatic circuit generation software may include a sigma delta modulator that is

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coupled to the feedback divider so as to control its division. More details

concerning fractional N synthesis may be found in "Method and Apparatus For A

Frequency Synthesizer Having a Compensated Sigma Delta Modulator Output

Signal" filed on September 27, 2000, provided U.S. Patent Application No.

09/672,178 and assigned to Parthus Technologies PLC of Dublin, Ireland.

Referring to the embodiment of Figure 3, the input and outputs of the circuit

to be automatically constructed have been defined 350 once a graphical user

interface has been presented 330 to the designer (and the designer has provided a

description 302 of the desired output clocks via the interface) and the VCO output

signal frequency and feedback divider ratio have been determined 340.

After the input and outputs have been defined 350, an analog PLL core may

be generated 360 and a behavioral level model may be generated 370. As seen in

the methodology of Figure 3, the generation 360 of an analog PLL core may be

embodied in the form of a transistor netlist 320 which is made available to: 1) the

designer for the purposes of completing the transistor level netlist of the

semiconductor chip; and 2) a subroutine that generates a layout tile 322 that

describes the physical layout of the analog PLL core.

Automatic Generation of Analog PLL Core

Figure 5 shows a methodology 560 that may be used to automatically

generate an analog PLL core. That is, the methodology 560 of Figure 5 may be

used to implement the methodology 360 of Figure 3. Referring to the methodology

560 of Figure 5 note that: 1) a VCO design is configured 561; 2) values for the loop

filter components 562 are determined; and 3) the remaining portions of the PLL are configured 563.

In an embodiment, the PLL to be implemented corresponds to the PLL design 570 shown in Figure 5. As seen in Figure 5, the PLL design 570 includes a VCO 511, a feedback divider 512, a phase detector 513 (which may also be referred to as a phase comparator 513), a charge pump 514, a loop filter 515, a lock detect circuit 516, a power down input 517, a reset input 518 and a lock detect 519 output. It is important to point out that other PLL designs may be utilized than the specific PLL design shown in Figure 5.

The functionality of the VCO 511, feedback divider 512, phase detector 513, charge pump 514, and loop filter 515 have already been described in the background. The lock detect 516 circuit triggers a signal when the phase detector 513 indicates the reference clock input is in phase with the divider 512 output signal. The power down input 517 cuts off power to the charge pump (e.g., to disable the PLL core during a low power mode). The reset input 518 forces the PLL to reacquire phase lock to the reference clock input signal.

The VCO may be configured 561 in light of the technology selection and the VCO output signal frequency that is submitted as an input to the PLL core generation sequence 560. In an embodiment, a "template" VCO design is implemented for all automatically generated designs. An exemplary template VCO design 520 is shown in Figure 5.

The template VCO design 520 of Figure 5 includes an odd number of cascaded inverters configured in a feedback arrangement (e.g., as seen in Figure 5,

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the last inverter in the cascade drives the first inverter in the cascade). Because an odd number of inverters are employed, the VCO design 520 is logically unstable and continuously oscillates from a 0 to a 1 and from a 1 to a 0.

The frequency of the VCO oscillation is a function of the propagation delay through each inverter and the number of inverters in the cascade. That is, one half of the oscillation period corresponds to one end to end ripple through the cascade of inverters. Thus, the VCO output signal frequency may be expressed as:

$$f_{vco} = 1/(2Mt_{PD})$$ Eqn. 2

where M is the odd number of inverters employed in the cascade and t_{PD} is the propagation delay through a single inverter.

The propagation delay t_{PD} through each inverter is controlled by the VCO input 523. For example, decreasing the voltage on the VCO input 523 will increase the propagation delay through each inverter while increasing the voltage on the VCO input 523 will decease the propagation delay through each inverter. Thus, increasing the voltage on the VCO input 523 increases the VCO oscillation frequency while decreasing the voltage on VCO input 523 decreases the VCO oscillation frequency.

In an embodiment, the template VCO is designed according to the contents of a look up table 525 that provides the number of inverter stages to use in the cascade ("M" as presented in Equation 2) for the particular technology and VCO output frequency inputs presented to the VCO configuration sequence 561. The contents of the look up table 525 are "filled in" beforehand by those offering the automatic PLL generation software to the designer.

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That is, for example, the look up table 525 may be sold as a database (e.g., as stored upon a Compac Disc - Read Only Memory (CD-ROM) or other machine readable medium) that supports the automatic PLL generation software 204 of Figure 2. The database may be upgraded over time (e.g., by supplying an newer version machine readable medium) to support more technologies (e.g., a newly supported semiconductor manufacturer or a more sophisticated manufacturing process that has been recently introduced).

The details of the look up table 525 are configured to produce a working VCO for a wide range of VCO output signal frequencies and technologies. For example, as described above, in an embodiment the look up table 525 contents indicate the number of inverters M that should be employed. The look up table 525 contents may also further include information that relates to the design of an inverter having an appropriate propagation delay t_{PD} for the technology input, the VCO output signal frequency input and the number of inverters M entry that resides along with such information. The VCO is configured 561 by looking up the number of inverters M and the inverter information for the particular input combination of technology and VCO output signal frequency.

For example, in an embodiment the inverter information is a transistor level netlist that corresponds to the design of an inverter having an appropriate propagation delay (e.g., proximate or equal to t_{PD} in Equation 2). Once the number of inverters M and the inverter design is obtained from the look up table 525, a complete VCO transistor level netlist is constructed having M of the looked up inverter designs arranged according to the structure of the VCO template 520.

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The performance of the inverter (and/or the performance of the VCO that is comprised of the inverter) may be simulated, inspected or otherwise qualified beforehand by those responsible for building the contents of the look up table. As a result, proper operation of the VCO is guaranteed before the look up table is actually used to support the automatic generation of designer's PLL.

Note that the look up table may be configured to have unique M and inverter design entries for a range of VCO output signal frequencies (e.g., as seen in look up table 525 of Figure 5 a first set of entries are listed for a frequency range f1 to f2 and a second set of entries are listed for a frequency range f2 to f3 where f1 < f2 < f3). Thus, for a particular technology selection, the same VCO design (in terms of the number of inverters M and the design of each inverter) will be constructed over a range of VCO output signal frequencies. This is possible because the VCO input voltage 523 needed to lock onto the reference clock may swing over a range of voltages (which correspond to a range of VCO output frequencies).

In other look up table embodiments, the inverter information may be parameter information (e.g., transistor dimensions, capacitance values, resistance values) that affect propagation delay. A pre-defined inverter template is used to construct (rather than look up) a transistor level netlist that corresponds to an inverter configured according to these parameters. Furthermore, it is important to point out that the VCO template 520 of Figure 5 is exemplary. As such, other embodiments may employ a template corresponding to another VCO architecture besides a cascade of an odd number of inverters.

Once the VCO design is configured 561, the values for the loop filter 515

components are determined 562. Referring to Figure 5, the values for the loop

filter 515 components include a resistor R1 in series with a capacitor C1. R1 and C1

are both shunted by a capacitor C2. Note that the loop filter 515 example of Figure

5 corresponds to a 2nd order loop. It is important to point out that loop filter

designs other than a 2nd order loop filter may be implemented according to the

design flow described below.

Figure 6 shows an embodiment of a methodology 662 that may be

employed to determine the loop filter components and the charge pump current

Io. In the embodiment of Figure 6, ranges for R1, C1, C2 and Io are obtained 601

from a lookup table 602. In a further embodiment, the ranges provided from the

look up table 602 are based upon the designer's technology choice (e.g., technology

choice 502 of Figure 5).

That is, based upon the ohms/square and capacitance/area of a particular

semiconductor manufacturing technology (and the impact that such parameters

have on the layout or performance of the PLL), a suitable range for each loop filter

component (e.g., a range for R1, a range for C1, and a range for C2) and a suitable

range for the charge pump current (Io) is determined beforehand by those offering

the automatic PLL generation software to the designer.

Note that with some enhancements to the loop filter design 515 shown in

Figure 5, the loop filter components R1, C1 and C2 may be configured to be on

chip. Techniques for integrating on chip loop filter components may be found in

an application entitled "Method and Apparatus For PLL With Improved Jitter

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Performance filed on May 17, 2000, provided U.S. Patent Application Number

09/574,683 and assigned to the Parthus Technologies,PLC. of Dublin, Ireland.

Alternatively, the loop filter components may be configured to be off chip.

Again, the look up table 602 may be sold as a database (e.g., as stored upon

a Compac Disc - Read Only Memory (CD-ROM) or other machine readable

medium) that supports the automatic PLL generation software 204 of Figure 2.

Furthermore, look up table 602 of Figure 6 may be merged or otherwise combined

with the other look up tables such as look up table 525 of Figure 5.

Once ranges for R1, C1, C2 and Io have been obtained 601, an iterative

process commences that determines a specific value for each of the parameters R1,

C1, C2 and Io that are to be used in the analog core of the PLL. Together, these

specific values correspond to a loop filter design and a charge pump design (also

referred to as loop configuration) that provide "favorable" PLL loop

characteristics. Loop characteristics are various indicia that describe the phase and

frequency response of the PLL.

In an embodiment, in order to determine the appropriate combination for

favorable PLL loop characteristics, all combinations of R1, C1, C2 and Io are tested

across their respective ranges (within an incremental resolution for each

parameter). The combination having the most favorable loop characteristics are

then used for the PLL's analog core.

For example, if R1 has a range from 1K ohms to 10K ohms, C1 has a range

from 50pf to 1000pf, C2 has a range of 1pf to 50pf, and Io has a range from 1uA to

50uA, for corresponding incremental resolutions of 100 ohms for R1, 10pF for C1,

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1pF for C2 and 1uA for Io, there exist 95 different values for R1 (e.g., 1K, 1.1K, 1.2K, etc.), 95 different values for C1, 50 different values for C2 and 50 different values for Io. This corresponds to 22,562,500 different combinations of R1, C1, C2 and Io values (i.e., 95x95x50x50 = 22,562,500).

In an embodiment of the iterative process mentioned above, one or more aspects the PLL's loop characteristics are calculated for each unique combination of R1, C1, C2 and Io values. In a further embodiment, in order to reduce the number of combinations, C1 may be deemed a function of C2. For example, in an embodiment, C1 = kC2 where k is a positive, real number that provides adequate frequency positioning of a pole and a zero associated with the loop filter (e.g., 10 < k < 30 such as k = 20.0).

By correlating each C1 value with a C2 value, the number of combinations is reduced. For example, using the example discussed just above, setting C1 = kC2 reduces the number of combinations to 237,500 (i.e., 95x50x50 = 237,500). As a result, the number of iterations that are performed is reduced and the amount of time consumed in producing the analog PLL core is lessened. Furthermore, note that a separate listing in the look up table 602 for C1 is not necessary because it may be determined from C2.

A detailed embodiment of an iterative process is shown in Figure 6. In the embodiment shown in Figure 6, a particular R1, C1, C2, and Io combination is selected 604 and aspects of the PLL's loop characteristics are determined 605. In the particular example of Figure 6, the loop characteristics to be determined correspond to the phase margin and clock suppression as calculated at variation

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extremes that are introduced by uncertainties in the selected technology (i.e, the semiconductor manufacturing process).

That is, the value of the resistor R1 and the value of the capacitors C1 and C2 may vary (within some tolerance) from batch to batch of manufactured semiconductor wafers. For example, R1 is guaranteed to be manufactured by the foundry only within R1+/- X where X is the manufacturing tolerance associated with R1. Other manufacturing tolerances may introduce variation into the gain of the VCO and the capacitors C1 and C2. Furthermore, environmental parameters (e.g., temperature) can also exhibit variation that affects the performance of the PLL.

Determining and checking the loop characteristics at the extremes of manufacturing and environmental related tolerances ensures that the analog PLL core will be acceptably functional regardless of the actual parameter value that is manufactured in a particular batch of wafers. As described immediately below, in the particular embodiment 605 shown in Figure 6, the loop's phase margin and clock suppression are determinations made at extreme ends of these tolerances.

Such determinations may be made because, after a combination of the R1, C1, C2 and Io parameters have been selected, all the information needed to build an understanding of the PLL's loop characteristics are readily available. That is, apart from the parameters mentioned just above, only the VCO transfer function is needed to complete a theoretical basis for determining the loop characteristics of a PLL. As is known in the art, the VCO transfer function may be expressed as K_{vco}/s where K_{vco} is the gain of the VCO (expressed in terms of Hz/volt) and s is –j2(pi)f.

K_{vco} and its manufacturing and temperature related uncertainty may be readily

determined because the VCO has already been configured beforehand (e.g., during

sequence 561 of Figure 5).

Referring to Figure 7, as an example, note that a pair of open loop PLL

transfer functions 701, 702 are displayed. Also shown in Figure 7 is a

corresponding phase curve 703, 704 for each transfer function 701, 702. That is,

phase curve 703 corresponds to open loop transfer curve 701 and phase curve 704

corresponds to open loop transfer curve 702.

The first pair of transfer function 701 and phase 703 curves correspond to

the PLL's loop characteristics at one extreme of the manufacturing and

environmental related variation discussed above while the second pair of transfer

function 702 and phase 704 curves correspond to the opposite extreme of the

manufacturing and environmental related variation discussed above.

Referring to Figure 7, the first pair of curves 701, 703 may be referred to as

the "worst case" manufacturing and environmental extreme because the transfer

curve 701 exhibits reduced gain (causing the PLL to lock onto a reference clock

input at a slower rate). Similarly, the second pair of curves 702, 704 may be

referred to as the "best case" manufacturing and environmental extreme because

the transfer curve 702 exhibits enhanced gain (causing the PLL to lock onto a

reference clock input at a faster rate).

In an embodiment, an understanding of the PLL at the worst case extreme is

developed with: 1) maximum R1; 2) maximum C2; 3) maximum C1 (which may be

expressed as maximum C2 multiplied by k); 4) minimum K_{vco} 5)maximum

temperature; and 6) minimum charge pump current Io. Similarly, an

understanding of the PLL at the best case extreme is developed with: 1) minimum

R1; 2) minimum C2; 3) minimum C1 (which may be expressed as minimum C2

multiplied by k); 4) maximum K_{vco}; 5) minimum temperature; and 6) maximum

charge pump current Io. In an embodiment, the designer is graphically presented

with the best case and worst case transfer function 701, 702 and phase curves 703,

704 (as seen in Figure 7) so that the designer can keep abreast of the PLL's loop

characteristics.

Phase margin is the difference between the phase delay through the loop

and −180 degrees (i.e., loop phase delay +180) when the loop transfer function

exhibits a gain of 0dB. For example, as seen in Figure 7, the phase margin for both

curves 703, 704 is approximately 50 degrees. Generally, the stability of the loop

degrades as the phase margin approaches −180. Thus, when analyzing the

manufacturing and environmental extremes, a parameter combination (R1, C1, C2,

Io) that produces a phase margin farther away from −180 is deemed "better than" a

parameter combination that produces a phase margin closer to −180. Clock

suppression, referring briefly back to the PLL model 570 of Figure 5, is the

attenuation through the loop filter 515 suffered by the charge pump 514 output

signal at its fundamental frequency.

As seen in the exemplary loop characteristic determination methodology

605 of Figure 6, the phase margin and clock suppression are determined 606 under

the worst case manufacturing and environmental extremes and are determined 607

under the best case manufacturing and environmental extremes. Thus a pair of phase margin values and a pair of clock suppression values are generated.

These are then compared 608 against minimum allowable design objectives (e.g., no worse than -40 dB clock suppression and no worse than -50 degrees phase margin). If the selected combination produces a phase margin or clock suppression that does not meet the minimum allowable design objectives, it is discarded from consideration as a possible combination that may be used.

If the selected combination at least meets the design objectives, the phase margin and clock suppression values of the selected combination are compared 609 against the best phase margin and clock suppression values that have been observed so far from the previously evaluated combinations. If the selected combination has better clock suppression and phase margin values (as compared to the best of the previously evaluated combinations) the previous combination is discarded from consideration as a possible combination that may be used, otherwise, the selected combination is discarded. The iterative process repeats until all the combinations have been evaluated, at which point a netlist 610 for the loop filter may be generated.

Referring back to Figure 5, once the loop filter 515 components have been configured 562, the VCO netlist and the loop filter netlist are integrated together with transistor level netlists for the remaining functional elements of the PLL (e.g., the feedback divider 518, the lock detect circuit 516, the phase detector 513, and the charge pump 514). These remaining netlists may be retrieved from another database having qualified designs for the selected technology At this point a

complete transistor level netlist 521for an analog PLL core has been developed. .

Note that some more details concerning possible embodiments for the feedback

divider are provided in more detail below with respect to Figures 11, 12, 13, and

14.

After the netlist 521 has been developed, it may be simulated by a simulator.

The simulator may be integrated into the automatic PLL circuit generation

software 214 of Figure 2, or a separate simulator may be utilized. Figure 8 shows

an exemplary graphical user interface 800 associated with an integrated simulator.

System parameters (i.e., parameters associated with the transistor level netlist of

the PLL analog core) are presented in a system parameter field 801. Note that Icp

is the same as the charge pump current Io, cs is the same as capacitor C1 and cp is

the same as capacitor C2.

Simulation parameters (i.e., parameters that control the simulation

environment) are also displayed in the simulation parameter field 802. Filter

leakage relates to a filter capacitor's ability to hold charge. Input jitter corresponds

to the jitter on the input reference clock to the PLL core. The designer is free to

change any of the system or simulation parameters. However, as an initial default,

the values corresponding to the automatically generated analog PLL core are

presented to the designer in the system parameter field 801 so that it may be

simulated.

Figure 9 shows an exemplary simulation report 900 that is presented to the

designer after a simulation is performed. The simulation report 900 includes

waveform displays for the input reference clock 901, the feedback divider output

902, and the VCO 903. Graphs of the VCO output signal period 904 and frequency 905 are also displayed. The designer is free to change the design of the analog PLL core (or at least simulate a conceived potential change to its design) via the system parameter interface 801 of Figure 8.

Automatic Generation of Behavioral Level Model

Recall that Figures 5 and 6 related to methodologies that may be used to automatically generate 360 an analog PLL core as seen in the methodology of Figure 3. The methodology of Figure 3, however, shows that a behavioral level model and synthesis script may also be generated 370. Behavioral level models were originally discussed with respect to Figure 2. A corresponding synthesis script for a behavioral level model can be developed by those of ordinary skill.

Recall from the discussion concerning Figure 2 that the PLL circuit design provided by the PLL generation software 204 may have both analog and digital components. For example, as seen in the exemplary behavioral level embodiment 1020 of Figure 10, the PLL circuit design is viewed as having an analog PLL core 1070 surrounded and/or supported by various digital functional units that add additional features to the functionality provided by the analog PLL core 1070.

A method for generating a transistor level netlist of an analog PLL core was just described in the preceding section. At the behavioral level, however, the analog PLL core 1070 may be treated as a "black box". That is, the analog constituents of the analog core (e.g., the loop filter, VCO, charge pump, phase detector, etc.) are not specifically described. Rather, the "black box" 1020 simply

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describes the designed for VCO output signal (e.g., by its frequency) and may also

describe temporal aspects of the analog PLL core that have been learned via the

simulation of the analog PLL core as described with respect to Figures 8 and 9.

For example, note that the analog PLL core described above (i.e., analog

core 520 of Figure 5) possesses a phase lock detect output 519. The phase lock

detect output signifies that the PLL has stabilized (i.e., has locked onto the

reference clock input 530 signal). As such, it may be used as a soft reset for

downstream digital circuitry that depends upon the various output clocks (clock_1,

clock_2, etc. as seen in Figure 10) produced by the PLL circuit 1020.

Thus, referring to Figure 10, when the lock detect output 1019 signal

changes state to reflect the PLL is locked, downstream circuitry comes out of reset

and begins to operate. The timing of the change of state (i.e., how long after a

reference clock input 1003 is applied or reset at the reset input 1018 occurs) may be

described to correspond to those characteristics demonstrated by the analog core's

simulation. Alternate PLL circuit embodiments may include digital circuitry that

uses the phase lock output 1019 as well.

Some possible digital circuits that may surround and/or support the

operation of the analog core 1020 so as to be described in a behavioral level

description of an automatically generated PLL circuit 1020 are also seen in Figure

10. For example, a divider 1002 may be placed between the reference clock input

1003 that is sent to the analog PLL core 1070 and a clock input 1004 that is actually

offered by the designer's circuit.

Inserting a divider 1002 at the input to the PLL (i.e. dividing the input clock

1004 frequency) may be used to increase the range of input to output frequencies

available from the PLL circuit. For example, a VCO output signal frequency of 15.0

MHz cannot be achieved with a basic feedback divider 512 (as seen in Figure 5)

and an input clock 1004 frequency of 12.0 MHz. Setting the input divider 1002

ratio to divide the input clock 1004 frequency by 4.0, however, allows a feedback

divider ratio of 5.0 to provide the desired setup.

Note also that this allows an automatic analog core routine (such as

described with respect to Figures 5 and 6) to "force" the use of an input reference

clock 1003 signal frequency that is more preferable for proper analog core

operation (e.g., in light of feedback division constraints, loop stability oriented

design rules, etc.) as compared to the designer's desired input clock 1004

frequency.

Recall from the discussion concerning Figure 4 that the output clocks to be

supplied by a PLL circuit 1020 (e.g., clock_1, clock_2, . . . clock_Z as seen in Figure

10) may be individually specified (as to the structure of their waveforms) by the

designer. Thus, as alluded to in the discussion of Figure 4, another digital circuit

that may be used to support the analog PLL core 1070 is a clock shaping circuit

1050 that crafts designer specified clock waveforms from the VCO output signal.

Figure 11 shows an embodiment 1150 of a design that may be used for the

clock shaping circuit 1050 of Figure 10. It is important to point out, however, that

other clock shaping circuits may be used. The clock shaping circuit 1150 of Figure

11 includes a shift register 1103_1, 1103_2, . . . 1103_z coupled in a feedback

arrangement (e.g., a last cell 1102 shifts its data to a first cell 1101) for each output clock Clock_1, Clock_2, . . . Clock_Z the designer specifies.

Each shift register 1103_1, 1103_2, . . . 1103_x is clocked by the VCO output signal. Thus, within each shift register 1103_1, 1103_2, . . . 1103_x, a cell will shift data into its neighboring cell at the VCO output signal frequency (e.g., on each rising edge or each falling edge of the VCO output signal). During an initial setup time (e.g., during power up) the patterns of each clock waveform are loaded into the cells of its corresponding shift register. After the setup, each shift register clocks out its cell data and the proper clock waveform appears on the clock output. The proper clock waveform is continuously clocked out because of the feedback arrangement discussed above.

Figure 12 demonstrates some examples of how a shift register may be loaded with information in order to craft an output clock having a desired waveform. A VCO output signal 1201 (used as a clocking source) and four clock waveforms 1202, 1203, 1204, 1205 are shown. For simplicity, the shift registers (not shown in Figure 12) used to produce the output waveforms 1202, 1203, 1204, 1205 are 8 bit registers. Thus, the loaded data 1206, 1207, 1208, 1209 for each waveform in Figure 12 is shown as eight bits.

A first example shows a "divide by 2" clock waveform 1202 that is generated from its corresponding shift register data 1205. The combination of loading a 10101010 pattern and clocking it out with the VCO output clock produces a 50% duty cycle signal having a frequency equal to one half of the VCO output clock frequency. In the second example, a "divide by 4" clock waveform

1203 is generated from its corresponding shift register data 1207. The combination of loading a 11001100 pattern and clocking it out with the VCO output clock produces a 50% duty cycle signal having a frequency equal to one fourth of the VCO output clock frequency.

The third example shows a "divide by 4" clock waveform 1204 having a 25% duty cycle that is generated from its corresponding shift register data 1208. The combination of loading a 10001000 pattern and clocking it out with the VCO output clock produces a 25% duty cycle signal having a frequency equal to one fourth of the VCO output clock frequency.

The fourth example shows a "divide by 4" clock waveform 1205 having a 25% duty cycle positioned at a phase offset of once VCO clock cycle with respect to the other clocks is generated from its corresponding shift register data 1209. The combination of loading a 01000100 pattern and clocking it out with the VCO output clock produces a 25% duty cycle with a phase offset of one VCO clock cycles having a frequency equal to one fourth of the VCO output clock frequency.

From these examples it can be seen that the frequency of an output clock may be established with the bit spacing (e.g., bit spacing 1210) between neighboring "0 to 1" transitions. It can also be seen that the duty cycle of an output clock may be established by controlling the "density of 1s" within the aforementioned bit spacing 1210 that establishes the clock's frequency. For example, within the bit spacing 1210 of waveform 1203 half or the bits are set at 1 (i.e., a 50% 1's density). This corresponds to a duty cycle of 50%. By comparison,

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within the bit spacing 1210 of waveform 1204 one fourth of the bits are set at 1 (i.e., a 25% 1's density). This corresponds to a 25% duty cycle.

Furthermore, from these examples it can also be seen that the phase of an output clock may be adjusted by effectively "shifting" a data pattern having the proper frequency and duty cycle before it is actually loaded into the shift register. That is, the data pattern 1209 is the same data pattern as data pattern 1208, except that data pattern 1209 is loaded into the shift register "as if" it has already been shifted by one cell.

A methodology designed consistently with the above observations may be used to translate a designer's desired clock waveform (e.g., as entered through a graphical user interface such as the graphical user interface 400 seen in Figure 4) into data that is loaded into a shift register responsible for producing the desired clock waveform. An example of such a methodology 1320 is shown in Figure 13.

First, the designer's desired frequency 1321 is translated 1322 into a number of bit spacings that are forcibly inserted between "0 to 1" transitions of the shift register data pattern. The designer's desired duty cycle 1323 is then translated 1324 into the appropriate "1's density" for each bit spacing within the data pattern. Finally, the designer's desired phase shift 1325 is translated 1326 by reforming the data pattern to look as if was already shifted within the shift register.

Note the size of a shift register controls the frequency division that may be implemented with an output clock. For example a 32 bit shift register allows for frequency divisions of 2, 4, 8, or 16. Similarly, a 24 bit register allows for frequency divisions of 3, 6 and 12 ; a 20 bit register allows for frequency divisions of 5 and 10;

a 14 bit register allows for frequency division by 7; and an 18 bit register allows for

frequency division by 9. Together, at least one of these registers allows for any

integer frequency division from 2 through 10.

The clock shaping circuit of Figure 11 and the methodology of Figure 1320

may be tailored to employ an appropriately sized shift register and data pattern

size depending on the frequency division desired by the designer.

Referring back to Figure 10, notice the presence of divide input 1030 (which

corresponds to divide input 530 of Figure 5). The divide input 1030 may be

applicable depending on the design of the divider used in the analog PLL core. In

some embodiments the divider may be an integer divider that is completely

configured during the analog core generation sequence. As such a divide input

1030 is not necessary.

In other cases, the appropriate feedback division may be externally

indicated to the analog core 1020 via a digital circuit (not shown in Figure 10) that

drives the division input 1030. For example, as mentioned above, a sigma delta

modulator circuit may be configured to drive the division input 1030 to provide for

non integer division in the feedback loop. The sigma delta modulator circuit may

be provided by the designer or the automatic PLL generation software. As another

example, the appropriate integer division may be indicated by a digital circuit that

drives the division input 1030.

Figure 14 shows a divider embodiment 1401 that may be employed to

perform frequency division. The divider embodiment 1401 of Figure 14 is

commonly referred to as a programmable divider. A programmable divider may

be used: 1) to feed a pattern generator within the clock shaping circuit 1050 of the

PLL circuit of Figure 10 (e.g., to craft the proper frequencies of the pattern

generator's output clocks); 2) as the divider 1002 between the input clock and the

reference clock of the PLL circuit of Figure 10; and/or 3) as the feedback divider

within the analog PLL core (e.g., such as divider 512 of Figure 5).

Programmable dividers are known in the art. A programmable divider is

provided with an input word (e.g., at the "divide" input as seen in Figure 14) that

controls the division performed by the divider. The use of programmable dividers

(within either an analog PLL core or a PLL circuit) may reduce the complexity of

an automatic PLL generation software program. That is, because the software can

configure the proper division simply by specifying what it should be (via the

divide word input), the complexity of the coding of an automatic PLL generation

software program may be reduced.

Automatic Generation of Layout Tile

Referring back to Figure 3, note that layout information (e.g., in the form of

a layout tile 322) may be provided to the designer as another output of an

automatic PLL generation software tool. In an embodiment, a layout tile 322 is

generated 380 of a PLL circuit·

Figure 15 shows a methodology that may be used to automatically

implement the layout of an analog PLL core or a PLL circuit. A physical layout

template corresponding to an analog PLL core is first retrieved 1501 from a

database (e.g., as a stored on a CD-ROM or other machine readable medium) used

to support the automatic PLL generation software program. The analog PLL core

550 shown in Figure 5 may be used to represent the template for an analog core. The analog core template 550 is an amount of semiconductor surface area having a block (also referred to an component block) for each of the various PLL core components (e.g., the VCO, the divider, the phase detector, the lock detect, the charge pump, and the loop filter).

A block is the layout information of a particular component positioned at its proper place in the template 550. For example, a VCO block 511 having the layout information of the VCO is located in the proper location for a VCO in a PLL core design.

The template with its blocks may be implemented in a GDS-II format. Note that the template 550 also possesses the interconnections between the components (e.g., a trace running between the loop filter and the VCO). Correspondingly, the blocks are configured with input and output traces that line up with the template's interconnection lines (e.g., a VCO block is configured with an input trace that lines up with the aforementioned template trace between the loop filter to the VCO).

Blocks may be static or configurable. Static blocks are not altered during the layout sequence. The complete layout of the static blocks may therefore be designed beforehand by those responsible for generating the data base. Thus, referring to Figure 15, after the template is retrieved 1501 from the data base, the layout of the template's static blocks have already been completed. In an embodiment, the phase detector and the lock detect circuit are both implemented as static blocks.

Configurable blocks may then be configured 1502. Configurable blocks are included in the template that was retrieved 1501 from the data base (as described above). However, unlike a static block, the automatic PLL generation software plays a role in defining the final layout information of a configurable block. Generally, configurable aspects of the layout sequence are coextensive with the specific circuit design items that the automatic PLL generation software has determined beforehand. Thus, configurable blocks tend to correspond to those components that the automatic PLL generation routine played a role in determining the design of (while static blocks tend to correspond to those components that the automatic PLL generation routine did not play a role in determining the design of).

For example, recall from the exemplary analog core design methodology 560 discussed above with respect to Figure 5 that the automatic PLL generation software routine was configured to determine the appropriate charge pump current for the analog PLL core but did not calculate any parameters associated with the design of the phase detector. As a result, the phase detector is implemented as a static block while the charge pump is implemented as a configurable block.

A configurable block, such as the charge pump block discussed just above, frequently has both static and configurable sections. The configurable sections of the configurable block correspond to those sections of the block that are affected by the automatic PLL generation software (e.g., the amount of current that a charge pump pushes/pulls to/from the loop filter).

The static portions of a configurable block correspond to those portions of the block that are not affected by the automatic PLL generation software (e.g., charge pump circuitry responsible for interpreting the phase detector output and enabling, in response, a current source to properly push current to or pull current from the charge pump). Thus, the static portions of a configurable block are not adjusted or tailored by the automatic PLL generation software while the configurable portions are.

Fig 16a relates to an approach for implementing a configurable portion of a charge pump block. Recall that the amount of charge pump current may be configured. As such, Figure 16a shows the portion 1601 of a charge pump design/layout that determines the amount of current pushed (or pulled) to (or from) the loop filter. Other portions of the loop filter design (i.e., the static portions) are not shown for simplicity.

Figure 16a shows an array of current sources. Note that, as designed into the configurable charge pump block by those responsible for developing the database from which the block was retrieved, the current sources are disconnected from the current flow input node 1601 and the current flow output node 1606. The automatic PLL generation software "connects" the number of current sources needed to produce the amount of current that was determined to be appropriate beforehand (e.g., from methodology 662 of Figure 6).

For example if each of the current sources in the array are 1uA current sources and the appropriate amount of charge pump current is 6uA, the automatic PLL generation software will "connect" 6 current sources to the input node 1601

(e.g., by connecting each of their A terminals to input node 1601) and to the output node 1602 (e.g., by connecting each of their B terminals to output node 1602).

In an embodiment, the configurable block includes enough current sources to provide the maximum charge pump current that the automatic PLL design tool is allowed to configure (e.g., for the target technology employed as established via a look up table such as look up table 602 of Figure 6 or otherwise). Thus, the template retrieved 1501 from the data base has layout information suitable to configure a maximum charge pump current (should such a charge a pump be designed).

Note that the array of current sources may be partitioned into current source groups of larger and smaller amounts of current. For example, in an embodiment a first partition includes 10uA current sources, a second partition includes 5uA current sources and third partition includes 1uA current sources. As a result, the automatic PLL generation software can configure 16uA of current by connecting a 10uA, 5uA and 1uA current source to the input node 1602 and output node 1606. Referring back to Figure 15, when the automatic PLL generation software program makes these connections it is configuring 1502 a configurable charge pump block. The process continues iteratively until each configurable block in the template has been configured.

The following discussion reviews some pertinent aspects of the configurable and static portions of various configurable PLL blocks. With respect to the VCO, recall that the inverter design used within the VCO may be retrieved from a pre-supplied data base that supports the automatic PLL generation program.

Likewise, the layout information for each inverter may be stored within and retrieved from a data base as well. As such, the layout of the inverter(s) within a VCO may be viewed as static.

Recall, however that the number of inverters to be used in the VCO was determined by the automatic PLL generation software (e.g., as discussed with respect to methodology 561 of Figure 5). As such the number of inverters contained in the VCO block are configurable. The automatic PLL generation software therefore builds the VCO block by stringing together in a cascade fashion the proper number of static inverter layout descriptions retrieved from the aforementioned data base. In an embodiment, the region of the template that is reserved for the VCO block is large enough to accommodate the largest number of cascaded inverters that could be designed by the automatic PLL generation tool.

If programmable dividers are used (as a feedback divider in the analog PLL core), the programmable divider is mostly static. That is, for fixed division, the configurable portion of the programmable divider may be limited to the proper value of the input divide word. As such, the automatic PLL generation software may be designed to connect each bit line of the input divide word to a pull up resistor or a pull down resistor so that proper input divide word is hardwired into the divider.

Note that a template for a PLL circuit (an example of which may be envisioned as template 1020 of Figure 2) may also be used to construct the layout of a PLL circuit. If shift registers are used to implement the dividers and clock waveform shaping circuitry (e.g., as described with respect to Figures 11, 12 and

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13) the automatic PLL generation software selects the appropriately sized shift register for the designed for division and also hardwires the proper word to be loaded into each shift register. In an embodiment, a PLL circuit template is configured to have a configurable number of openings, each sufficient for the largest sized register that may be used. The automatic PLL generation software then drops an appropriately sized register into each opening for each divided down signal that is needed.

With respect to the loop filter, recall that the entirety of the loop filter may be designed by the automatic PLL generation circuit (e.g., by the methodology 562 of Figure 5 where R1, C1 and C2 are determined). As such, the entire loop filter may be viewed as configurable. Figure 16B shows an embodiment 1610 of an approach that may be used to configure the loop filter resistor R1.

Figure 16B shows a string of cascaded resistances 1612. The proper loop filter resistance is configured by "tapping" a connection from the string at to the output node 1611. The position of the tapped connection determines the value of the loop resistance. For example, a connection tapped from point "4" corresponds to less resistance than a connection tapped from point "N-1". In an embodiment each discrete resistor is given a value of 100ohms, thus a 2K resistor is formed by tapping after the 20th resistance. The total resistance of the cascaded resistances 1612 (e.g., the resistance if a connection were tapped from point N) may be designed to be the largest resistance the automatic PLL design tool could design for a loop filter resistor.

The loop filter capacitors are configured by adjusting their size. That is, as is

known in the art, the value of a capacitance is a function of its surface area. The

automatic PLL generation software determines the appropriate surface area for the

capacitor and forms an appropriately sized capacitor. Note that a variable

template block size (rather than a fixed template block size) may be used. As such,

the automatic PLL generation program adjusts the size of the block for the loop

filter capacitors as it forms the PLL core. This is done because the "maximum"

capacitance that could be used in a PLL core can be very large. To configure a

template with a maximum sized capacitor would consume too much

semiconductor surface area.

Once a template has configured all of its configurable blocks, the template

has been "completed". A "completed" template may be referred to as a layout tile

(such as layout tile 322 of Figure 3). Note that a PLL circuit template may include a

configurable block that corresponds to the analog core.

Additional Comments

It is to be understood that embodiments of this invention may be used as or

to support software programs executed upon some form of processing core (such

as the CPU of a computer) or otherwise implemented or realized upon or within a

machine readable medium. A machine readable medium includes any mechanism

for storing or transmitting information in a form readable by a machine (e.g., a

computer). For example, a machine readable medium includes read only memory

(ROM); random access memory (RAM); magnetic disk storage media; optical

storage media; flash memory devices; electrical, optical, acoustical or other form of propagated signals (e.g., carrier waves, infrared signals, digital signals, etc.); etc.

In the foregoing specification, the invention has been described with reference to specific exemplary embodiments thereof. It will, however, be evident that various modifications and changes may be made thereto without departing from the broader spirit and scope of the invention as set forth in the appended claims. The specification and drawings are, accordingly, to be regarded in an illustrative rather than a restrictive sense.

CLAIMS

What is claimed is: 1.   A method, comprising:

automatically generating a design for an analog phase lock loop (PLL) core in

response to a desired clock frequency.

AMENDED CLAIMS
[received by the International Bureau on 30 March 2001 (30.03.01);
original claim 1 replaced by new claims 1-47 (9 ages)]

1. A method, comprising:

automatically generating a design for an analog phase lock loop (PLL) core in

response to a desired clock frequency.

2. The method of claim 1 wherein said design corresponds to a transistor level

netlist.

3. The method of claim 2 further comprising automatically generating, in

response to said automatically generated transistor level netlist of said analog PLL core, a

layout tile that contains a layout of said analog PLL core.

4. The method of claim 3 wherein said layout tile is within a GDS-II format.

5. The method of claim 3 further comprising laying out a semiconductor chip,

said semiconductor chip layout including said layout tile.

6. The method of claim 5 further comprising integrating said analog PLL core

transistor level netlist into a transistor level netlist of said semiconductor chip.

7. The method of claim 6 further comprising verifying said semiconductor chip

layout by comparing connections described in said semiconductor chip layout against

connections described in said semiconductor chip transistor level netlist.

8. The method of claim 7 further comprising checking said verified layout for

compliance with design rules for a semiconductor chip manufacturing process.

9.   The method of claim 8 further comprising generating masks for said semiconductor chip after said verified semiconductor chip layout design rule check is completed.

10. The method of claim 9 further comprising manufacturing a semiconductor chip with said masks.

11. A method, said method comprising:

a.   calculating a phase lock loop (PLL) voltage controlled oscillator (VCO) output signal frequency in response to a desired output clock frequency;

b.   calculating a feedback divider ratio for said PLL in response to said VCO output signal frequency; and

c.   generating a transistor level netlist for an analog PLL core, said analog PLL core having a VCO with said VCO output signal frequency, said analog PLL core having a feedback divider with said feedback divider ratio, wherein said calculating a PLL VCO output signal frequency, said calculating a feedback divider ratio and said generating a transistor level netlist are each performed with one or more software routines.

12. The method of claim 11 further comprising generating, in response to said generated transistor level netlist of said analog PLL core, a layout tile that contains a layout of said analog PLL core, said generating a layout tile performed with one or more software routines.

13. The method of claim 12 wherein said layout tile is within a GDS-II format.

14. The method of claim 12 further comprising laying out a semiconductor chip, said semiconductor chip layout including said layout tile.

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15. The method of claim 14 further comprising integrating said analog PLL core transistor level netlist into a transistor level netlist of said semiconductor chip.

16. The method of claim 15 further comprising verifying said semiconductor chip layout by comparing connections described in said semiconductor chip layout against connections described in said semiconductor chip transistor level netlist.

17. The method of claim 16 further comprising checking said verified layout for compliance with design rules for a semiconductor chip manufacturing process.

18. The method of claim 17 further comprising generating masks for said semiconductor chip after said verified semiconductor chip layout design rule check is completed.

19. The method of claim 18 further comprising manufacturing a semiconductor chip with said masks.

20. A method, said method comprising:

a.   presenting a graphical user interface (GUI) that allows a designer to enter a desired output clock frequency;

b.   calculating a phase lock loop (PLL) voltage controlled oscillator (VCO) output signal frequency in response to said desired output clock frequency;

c.   calculating a feedback divider ratio for said PLL in response to said VCO output signal frequency; and

d.   generating a transistor level netlist for an analog PLL core, said analog PLL core having a VCO with said VCO output signal frequency, said analog PLL core

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having a feedback divider with said feedback divider ratio, wherein said presenting a GUI, said calculating a PLL VCO output signal frequency, said calculating a feedback divider ratio and said generating a transistor level netlist are each performed with one or more software routines.

21. The method of claim 20 wherein said GUI further allows said designer to enter a desired phase position for said output clock.

22. The method of claim 21 wherein said GUI further comprises a delay button that allows said designer to introduce a phase lag to said output clock.

23. The method of claim 21 wherein said GUI further comprises an advance button that allows said designer to introduce a phase lead to said output clock.

24. The method of claim 20 wherein said GUI further allows said designer to enter a desired duty cycle for said output clock.

25. The method of claim 20 wherein said GUI further comprises a window having a waveform display of said output clock.

26. The method of claim 25 wherein said GUI further comprises a zoom out button that triggers a zoomed out display of said output clock waveform.

27. The method of claim 25 wherein said GUI further comprises a zoom in button that triggers a zoomed in display of said output clock waveform.

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28. The method of claim 25 wherein said GUI further comprises a pan right button that adjusts to the right said output clock waveform display.

29. The method of claim 25 wherein said GUI further comprises a pan left button that adjusts to the left said output clock waveform display.

30. A method, said method comprising:

a.   presenting a graphical user interface (GUI) that allows a designer to enter a desired output clock frequency;

b.   calculating a phase lock loop (PLL) voltage controlled oscillator (VCO) output signal frequency in response to said desired output clock frequency;

c.   calculating a feedback divider ratio for said PLL in response to said VCO output signal frequency;

d.   generating a transistor level netlist for an analog PLL core in response to said VCO output signal frequency and said feedback divider ratio, said analog PLL core having a VCO with said VCO output signal frequency, said analog PLL core having a feedback divider with said feedback divider ratio;

e.   generating a layout tile of said analog PLL core in response to said transistor netlist; and

f.   generating a behavioral level model of a PLL circuit in response to said VCO output signal frequency, said behavioral level model including a behavioral level description of said analog PLL core, said PLL circuit including a clock shaping circuit that crafts said desired output clock from said VCO output signal, wherein said presenting a GUI, said calculating a PLL VCO output signal frequency, said calculating a feedback divider ratio, said generating a transistor level netlist and said generating a behavioral level model are each performed with one or more software routines.

31. The method of claim 30 wherein said GUI further allows said designer to enter a desired phase position for said output clock.

32. The method of claim 31 wherein said GUI further comprises a delay button that allows said designer to introduce a phase lag to said output clock.

33. The method of claim 31 wherein said GUI further comprises an advance button that allows said designer to introduce a phase lead to said output clock.

34. The method of claim 30 wherein said GUI further allows said designer to enter a desired duty cycle for said output clock.

35. The method of claim 30 wherein said GUI further comprises a window having a waveform display of said output clock.

36. The method of claim 35 wherein said GUI further comprises a zoom out button that triggers a zoomed out display of said output clock waveform.

37. The method of claim 35 wherein said GUI further comprises a zoom in button that triggers a zoomed in display of said output clock waveform.

38. The method of claim 35 wherein said GUI further comprises a pan right button that adjusts to the right said output clock waveform display.

39. The method of claim 35 wherein said GUI further comprises a pan left button that adjusts to the left said output clock waveform display.

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40.   The method of claim 30 wherein said PLL circuit further comprises a divider circuit that receives an input clock, said divider circuit producing a reference clock as an input to said analog PLL core, said reference clock having a reference clock frequency determined by said divider.

41.   The method of claim 40 wherein said GUI allows said designer to enter a frequency for said input clock.

42.   The method of claim 41 further comprising determining a division to be performed by said divider circuit, said division making said reference clock frequency equal to said VCO output signal frequency divided down by said feedback divider ratio, said determining a division performed with one or more software routines.

43. The method of claim 30 wherein said behavioral level model of said PLL · circuit further comprises a soft reset that is derived from a lock detect output provided by said analog PLL core.

44.   The method of claim 30 further comprising providing said behavioral level model of said PLL circuit in a VHDL compatible format.

45. The method of claim 30 further comprising providing said behavioral level model of said PLL circuit in Verilog compatible format.

46. The method of claim 30 further comprising providing components of said behavioral level model described in an RTL HDL compatible format.

47. The method of claim 30 further comprising providing a synthesis script for said behavioral level model.

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48. The method of claim 30 further comprising simulating said behavioral level model of said PLL circuit.

49. The method of claim 30 further comprising creating, from said behavioral level model, an RTL netlist of those portions of said PLL circuit that are digital.

50. The method of claim 49 further comprising synthesizing said RTL netlist into a gate level netlist of those said portions of said PLL circuit that are digital.

51. The method of claim 49 further comprising performing timing analysis upon said gate level netlist.

52. The method of claim 30 further comprising integrating layout information that describes digital portions of said PLL circuit with said layout tile to form a layout of said PLL circuit having said analog PLL core.

53. The method of claim 30 further comprising integrating a transistor level netlist that describes digital portions of said PLL circuit with said transistor level netlist of said analog PLL core to form a transistor level netlist of said PLL circuit having said analog PLL core.

54. The method of claim 30 further comprising simulating said transistor level netlist of said analog PLL core.

55. The method of claim 54 further comprising providing a second GUI that presents results of said simulation to said designer.

56. A machine readable medium having stored thereon sequences of instructions which are executable by a digital processing system, and which, when executed by the digital processing system, cause the system to perform a method comprising:

automatically generating a design for an analog phase lock loop (PLL) core in response to a desired clock frequency.

57. A machine readable medium having stored thereon sequences of instructions which are executable by a digital processing system, and which, when executed by the digital processing system, cause the system to perform a method comprising:

a.   calculating a phase lock loop (PLL) voltage controlled oscillator (VCO) output signal frequency;

b.   calculating a feedback divider ratio for said PLL in response to said VCO output signal frequency; and

c.   generating a transistor level netlist for an analog PLL core, said analog PLL core having a VCO with said VCO output signal frequency, said analog PLL core having a feedback divider with said feedback divider ratio.

58. A machine readable medium having stored thereon sequences of instructions which are executable by a digital processing system, and which, when executed by the digital processing system, cause the system to perform a method comprising:

a.   presenting a graphical user interface (GUI) to a designer that allows said designer to enter a desired output clock frequency;

b.   calculating a phase lock loop (PLL) voltage controlled oscillator (VCO) output signal frequency in response to said desired output clock frequency;

c.   calculating a feedback divider ratio for said PLL in response to said VCO output signal frequency; and

d.   generating a transistor level netlist for an analog PLL core, said analog PLL core having a VCO with said VCO output signal frequency, said analog PLL core having a feedback divider with said feedback divider ratio.

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FIG. 1

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FIG. 2

Description Of Output Clocks 302

Input Signed
Frequency
301

Of Output Clocks
And The Frequency
Of Each
304

Phase Position And
Duty Cycle Of Each
Output Clock
305

Target
Technology
303

Automatically
Generate
PLL
Circuit
314

Present GUI
to Designer
330

Compute VCO
Output Signal
Frequency and
Feedback Divider
Ratio   340

Generate
Description
of Inputs
And Outputs
350

Generate
Behavioral
Level
Model
370

Generate
Analog
PLLCore
360

Synthesis
Script
323

Generate
Layout
Tile   380

Behavioral
Level
Model
320

Transistor
Level
Netlist
321

Layout
Tile
322

FIG. 3

FIG. 4

FIG. 5

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FIG. 6

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GAIN/PHASE versus Frequency   X

Phase Margin 50 degrees   Phase Margin1 49 degrees

Reference Clock suppression 41dbs

FIG. 7

FIG. 8

FIG. 9

FIG. 10

FIG. 11

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FIG. 12

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1320

Desired Output
Clock
Frequency
1321

Compute
Bit Spacing
Size

1322

Desired Duty
Cycle
1323

Compute
1's Density

1324

Desired Phase
Shift
1325

"shift"
Data
Pattern

1326
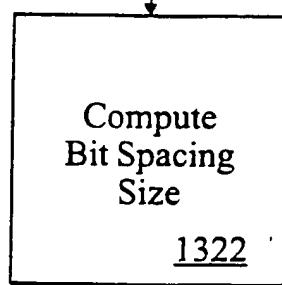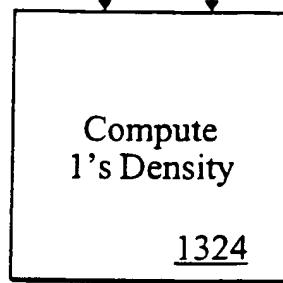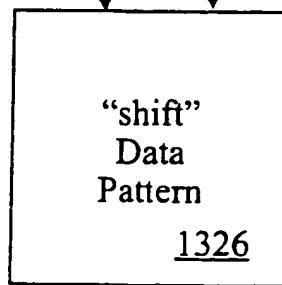
FIG. 13

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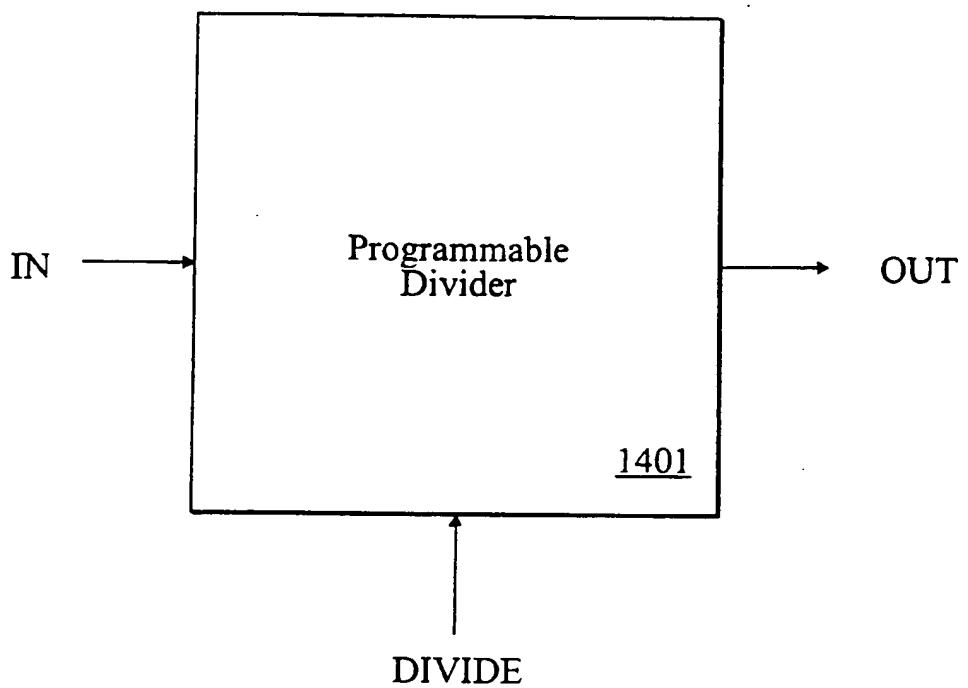

FIG. 14
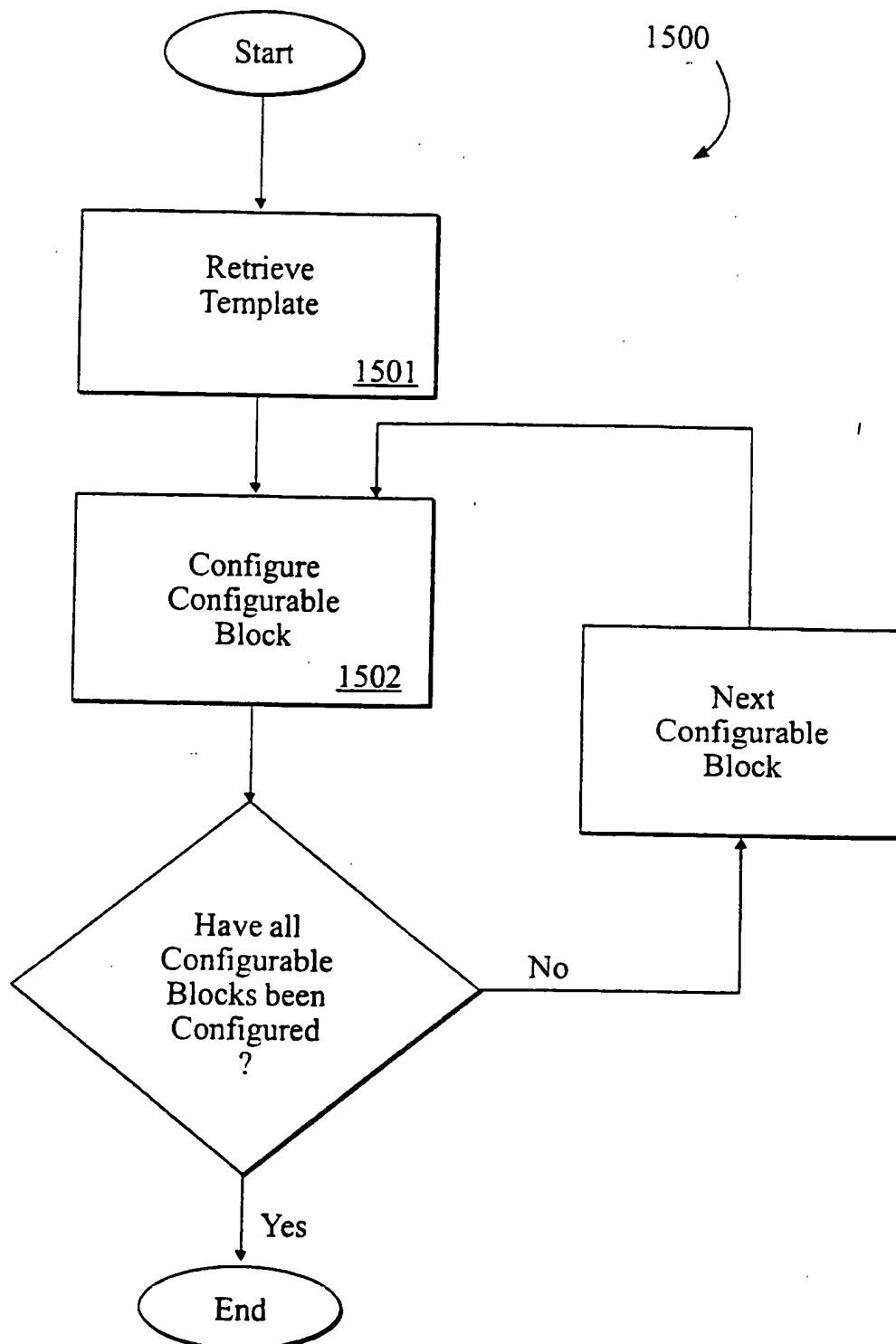
FIG. 15

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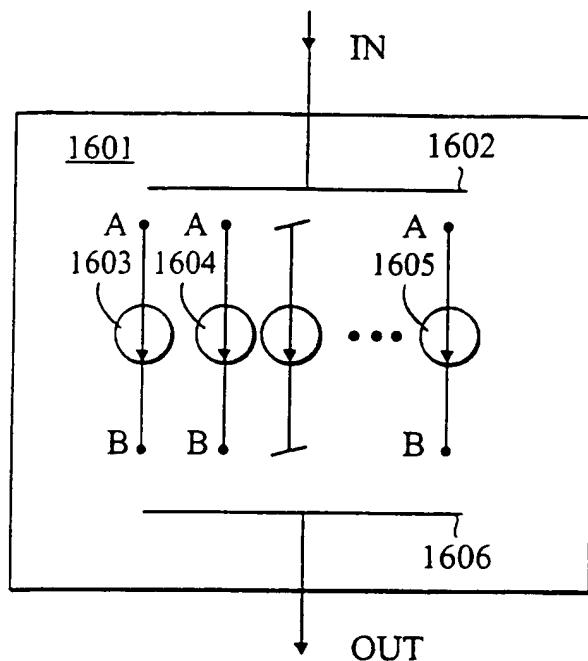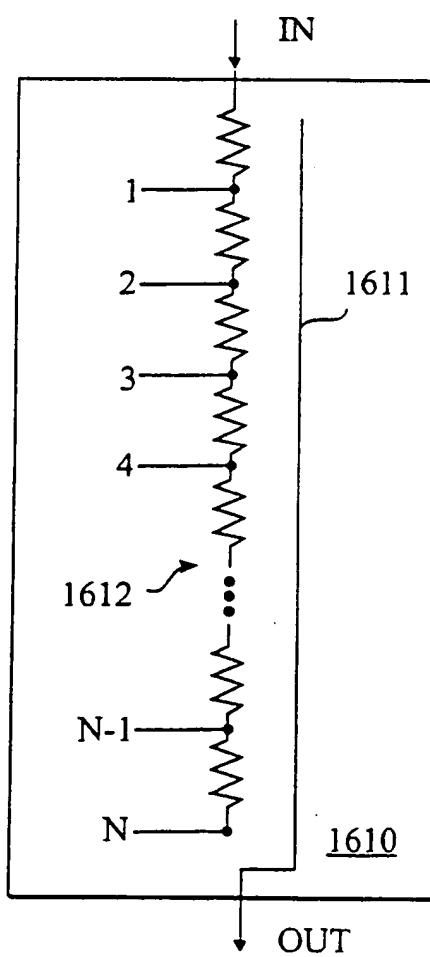
FIG. 16A

FIG. 16B

INTERNATIONAL SEARCH REPORT

A.	CLASSIFICATION OF SUBJECT MATTER

IPC(7) :H03L 07/06

US CL :331/1R, 18, 25

According to International Patent Classification (IPC) or to both national classification and IPC

B.	FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

U.S. : 331/1R, 1A, 16, 18, 25, 57, 116 R, 116FE, 117R, 117FE, 177R, 177V, 179

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

NONE

Electronic data base consulted during the international search (name of data base and, where practicable, search terms used)

NONE

C.	DOCUMENTS CONSIDERED TO BE RELEVANT

Category*	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	US 5,594,391 A (YOSHIZAWA) 14 January 1997 (14.01.97), see entire document, especially column 2, lines 20-21.	1

☐ Further documents are listed in the continuation of Box C. ☐ See patent family annex.

*	Special categories of cited documents:	"T"	later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention
"A"	document defining the general state of the art which is not considered to be of particular relevance		
"E"	earlier document published on or after the international filing date	"X"	document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone
"L"	document which may throw doubt on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified)	"Y"	document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art
"O"	document referring to an oral disclosure, use, exhibition or other means		
"P"	document published prior to the international filing date but later than the priority date claimed	"&"	document member of the same patent family

Date of the actual completion of the international search	Date of mailing of the international search report
16 JANUARY 2001	30 JAN 2001

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